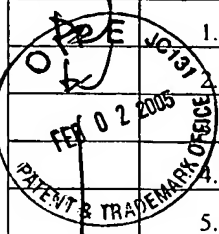
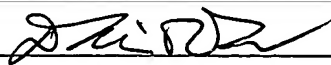


Form PTO-1449		U.S. Department of Commerce Patent and Trademark Office		Attorney Docket No. 5308-394		Serial No. 10/811,350	
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				Applicant: Gerald H. Negley			
				Filing Date: March 26, 2004		GAU: 2812	
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	20.	Pearson, S.J., "Wet and Dry Etching of SiC," <i>Process Technology for Silicon Carbide Devices</i> , pp. 85-92. Ch. 4 (2002).					

Examiner:



Date Considered:

8/2/06

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Substitute form 1449A/PTO		OTPE JC184 JUL 01 2005 PATENT & TRADEMARK OFFICE		Complete if Known		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number		10/811,350		
		Filing Date		March 26, 2004		
		First Named Inventor		Gerald H. Negley		
		Group Art Unit		2812		
		Examiner Name		TBA		
Sheet	1	of	1	Attorney Docket Number		5308-394

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Examiner Signature	<i>Lawrence</i>	Date Considered	8/2/06
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